Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/510,591	KLOEN ET AL.
Examiner	Art Unit
Chris C. Chu	2815

	SEARCHED				
Class	Subclass	Date	Examiner		
257	E23.054, E23.124, 678 & 787	11/10/2006	C.C.		
257	700 & 781	11/10/2006	C.C.		
257	786 & 738	11/10/2006	C.C.		
257	737 & 684	11/10/2006	C.C.		
438	124 & 106	11/10/2006	C.C.		

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
As same	as above	11/10/2006	c.c.	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; FPRS; and IBM_TDB;	11/10/2006	C.C.		
				
				